INFORMATION DISCLOSURE CITATION IN AN APPLICATION				ATTY. DOCKETNO., 4590-383		U.S. PATENZAL		
				APPLICANT Afshin ZIAEI et al.				
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RSP	Liu Y et al: "High-Isolation Bst-Mems Switches" 2002 IEEE Mtt-S International Microwave Syposium Digest (IMS 2002). Seattle, WA, June 2-7, 2002, IEEE MTT-S International Microwave Symposium, New York, NY vol. 1 of 3 June 2, 2002, pages 227-230.							
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EXAMINER	S Patel DATE CONSIDERED 02/27/07							

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.